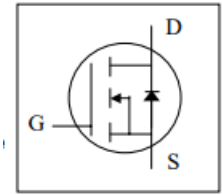


## 200V N-Channel Enhancement Mode MOSFET

### Description

The AP18N20D/Y is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system miniaturization and higher efficiency.



### General Features

VDS =200V, ID =18A  
 RDS(ON) <0.15Ω@ VGS=10V



### Application

Uninterruptible Power Supply(UPS)  
 Power Factor Correction (PFC)



### Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP18N20D	TO-252-3L	A18N20D XXX YYYY	2500
AP18N20Y	TO-251-3L	AP18N20Y XXX YYYY	4000

### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ , unless otherwise noted

Parameter	Symbol	Value	Unit
Drain-Source Voltage (VGS = 0V)	VDSS	200	V
Continuous Drain Current	ID	18	A
Pulsed Drain Current	IDM	72	A
Gate-Source Voltage	VGSS	±20	V
Single Pulse Avalanche Energy	EAS	340	mJ
Avalanche Current	IAR	15	A
Repetitive Avalanche Energy	EAR	8.3	mJ
Power Dissipation (TC = 25°C)	PD	104	W
Operating Junction and Storage Temperature Range	TJ, Tstg	-55~+150	°C
Thermal Resistance, Junction-to-Case	RthJC	1.2	°C/W
Thermal Resistance, Junction-to-Ambient	RthJA	60	

## 200V N-Channel Enhancement Mode MOSFET

**Electrical Characteristics** at  $T_J = 25\text{ }^\circ\text{C}$  unless otherwise specified

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	200	--	--	V
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 200V, V_{GS} = 0V, T_J = 25^\circ C$	--	--	5	$\mu A$
		$V_{DS} = 160V, V_{GS} = 0V, T_J = 125^\circ C$	--	--	100	
Gate-Source Leakage	IGSS	$V_{GS} = \pm 20V$	--	--	$\pm 100$	nA
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.2	1.6	2.5	V
Drain-Source On-Resistance (Note3)	RDS(on)	$V_{GS} = 10V, I_D = 9A$	--	0.12	0.15	$\Omega$
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 25V, f = 1.0MHz$	--	1318	--	$\mu F$
Output Capacitance	$C_{oss}$		--	180	--	
Reverse Transfer Capacitance	$C_{rss}$		--	75	--	
Total Gate Charge	$Q_g$	$V_{DD} = 160V, I_D = 18A, V_{GS} = 10V$	--	41	--	nC
Gate-Source Charge	$Q_{gs}$		--	5.5	--	
Gate-Drain Charge	$Q_{gd}$		--	19.5	--	
Turn-on Delay Time	$t_{d(on)}$	$V_{DD} = 100V, I_D = 18A, R_G = 25\ \Omega$	--	24	--	ns
Turn-on Rise Time	$t_r$		--	45	--	
Turn-off Delay Time	$t_{d(off)}$		--	101	--	
Turn-off Fall Time	$t_f$		--	95	--	
Continuous Body Diode Current	$I_S$	$T_C = 25\text{ }^\circ C$	--	--	18	A
Pulsed Diode Forward Current	ISM		--	--	72	
Body Diode Voltage	$V_{SD}$	$T_J = 25^\circ C, I_{SD} = 18A, V_{GS} = 0V$	--	--	1.4	V
Reverse Recovery Time	$t_{rr}$	$V_{GS} = 0V, I_S = 18A, di_f/dt = 100A/\mu s$	--	230	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	1.8	--	$\mu C$

### Notes

1. Repetitive Rating: Pulse width limited by maximum junction temperature
2.  $I_{AS} = 15A, V_{DD} = 50V, R_G = 25\ \Omega, \text{Starting } T_J = 25\text{ }^\circ C$
3. Pulse Test: Pulse width  $\leq 300\mu s, \text{Duty Cycle } \leq 1\%$

## 200V N-Channel Enhancement Mode MOSFET

### Typical Characteristics

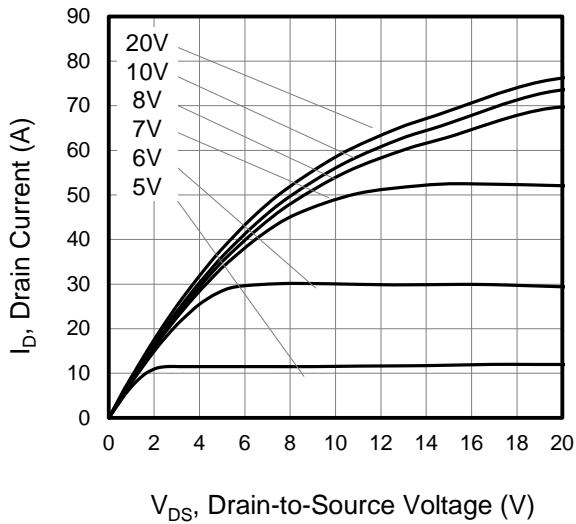


Figure 1. Output Characteristics ( $T_J = 25^\circ\text{C}$ )

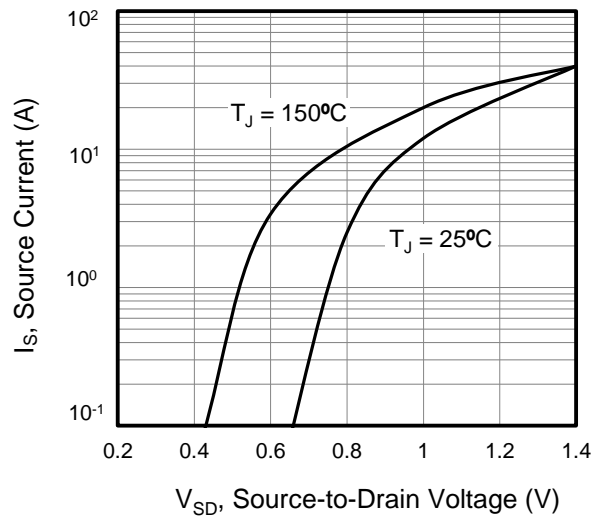


Figure 2. Body Diode Forward Voltage

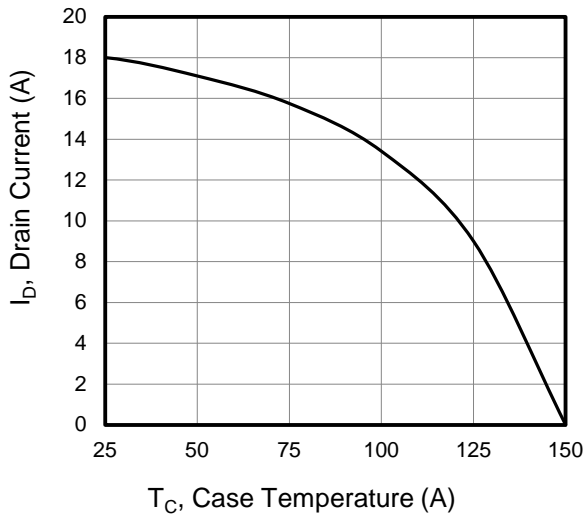


Figure 3. Drain Current vs. Temperature

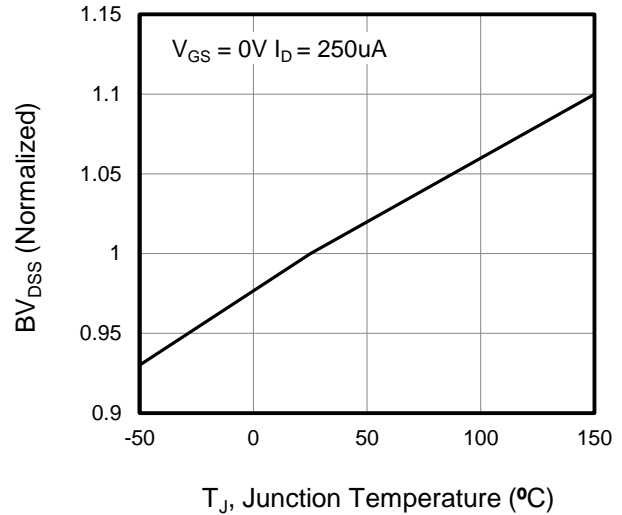


Figure 4.  $BV_{DSS}$  Variation vs. Temperature

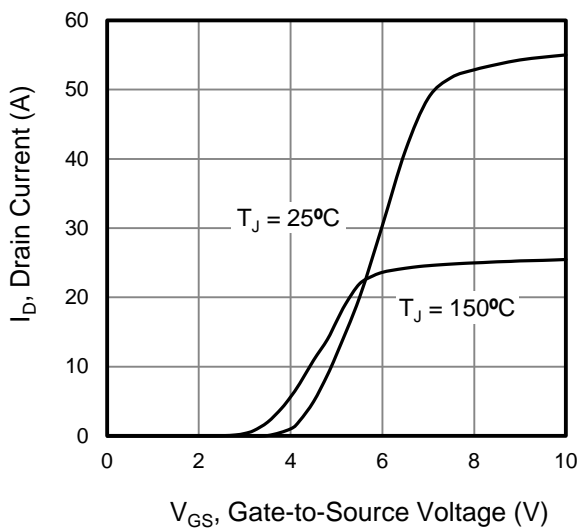


Figure 5. Transfer Characteristics

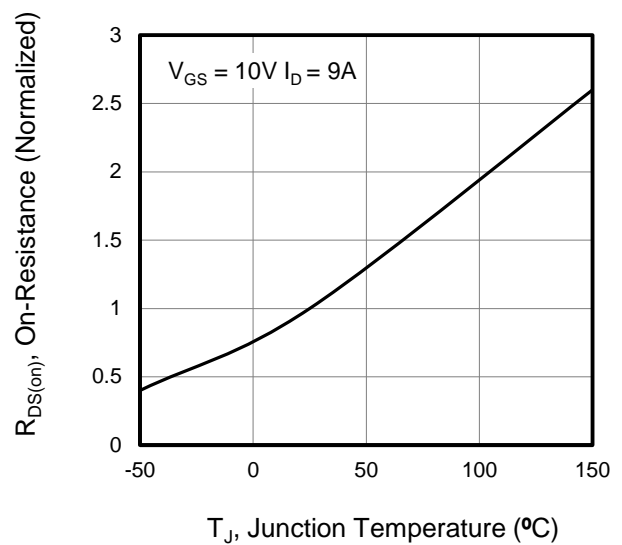
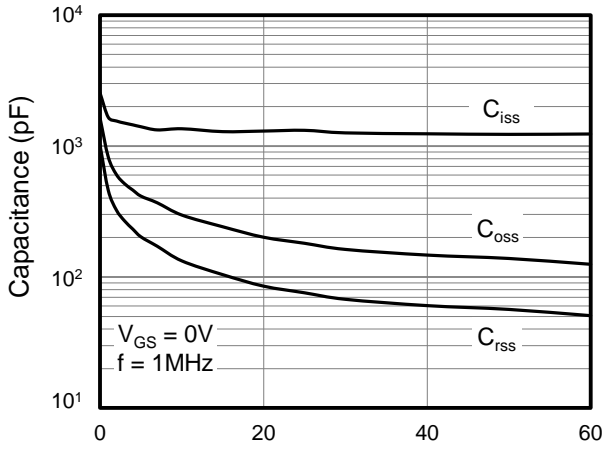
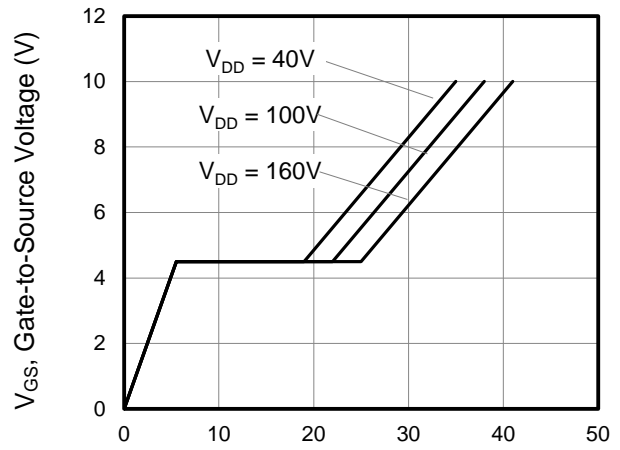


Figure 6. On-Resistance vs. Temperature

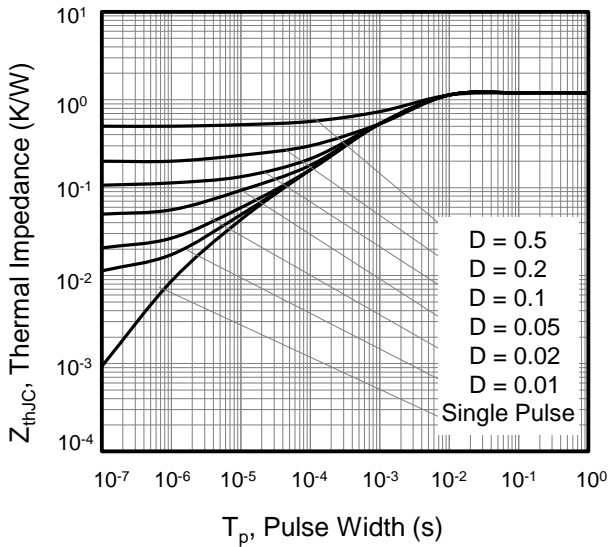
**200V N-Channel Enhancement Mode MOSFET**



$V_{DS}$ , Drain-to-Source Voltage (V)  
**Figure 7. Capacitance**

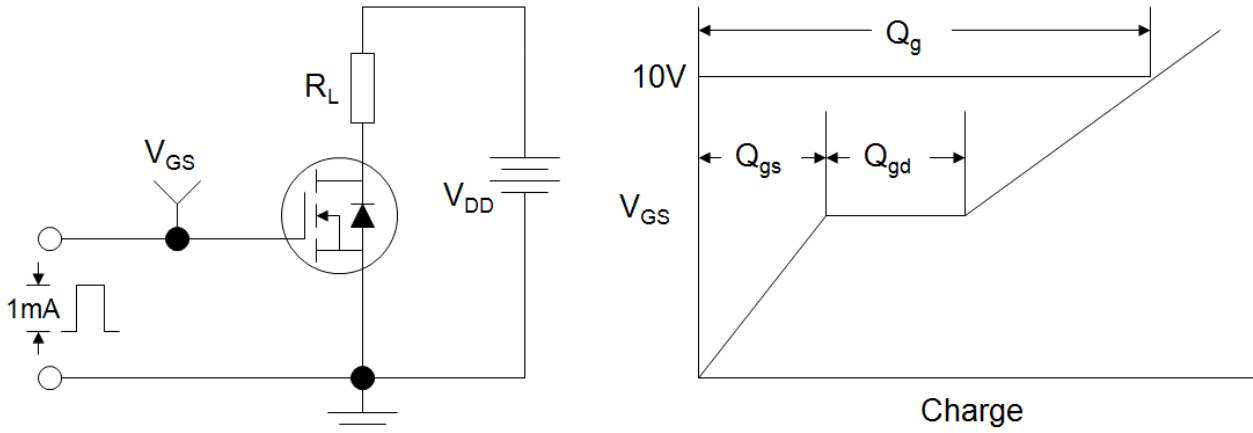


$Q_g$ , Total Gate Charge (nC)  
**Figure 8. Gate Charge**

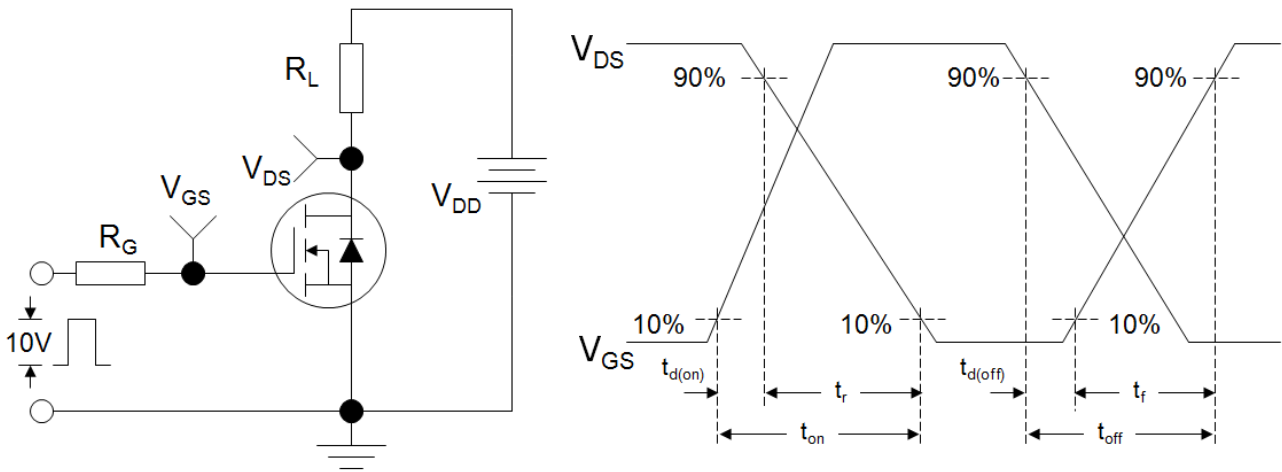


$T_p$ , Pulse Width (s)  
**Figure 10. Transient Thermal Impedance**

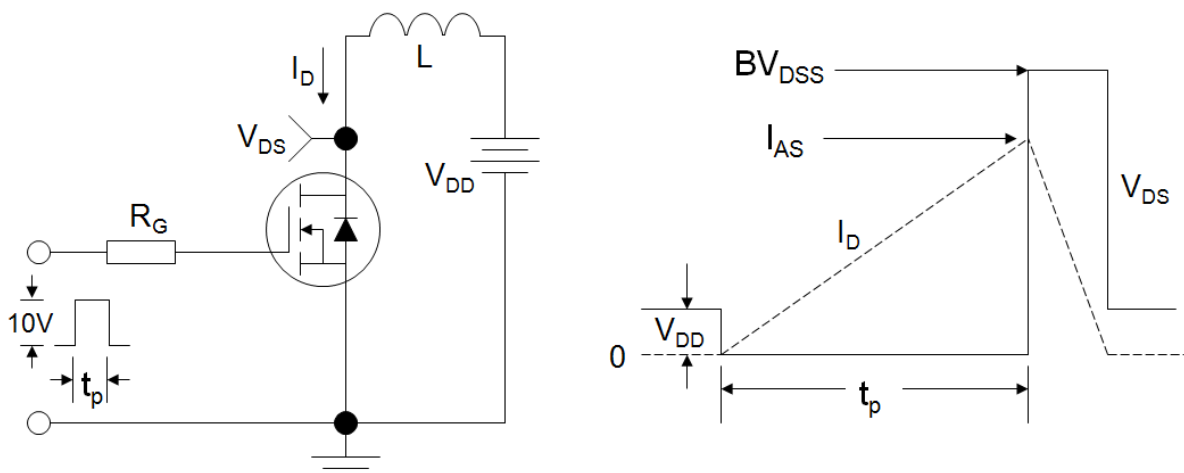
**200V N-Channel Enhancement Mode MOSFET**



**Figure A: Gate Charge Test Circuit and Waveform**



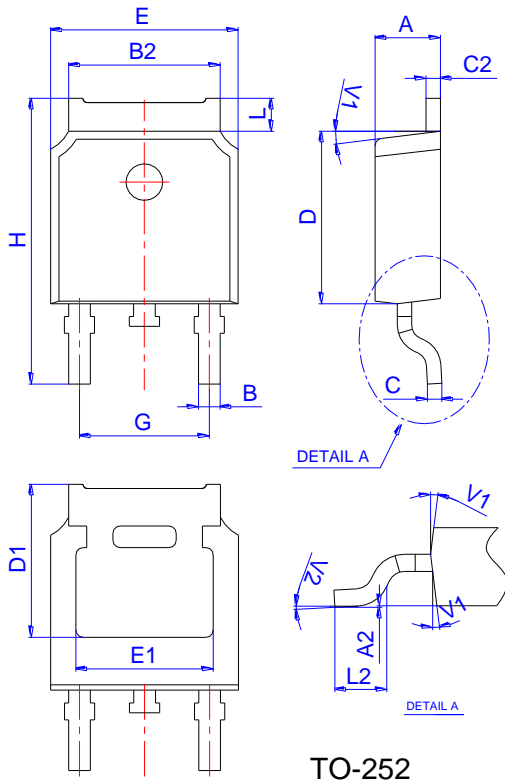
**Figure B: Resistive Switching Test Circuit and Waveform**



**Figure C: Unclamped Inductive Switching Test Circuit and Waveform**

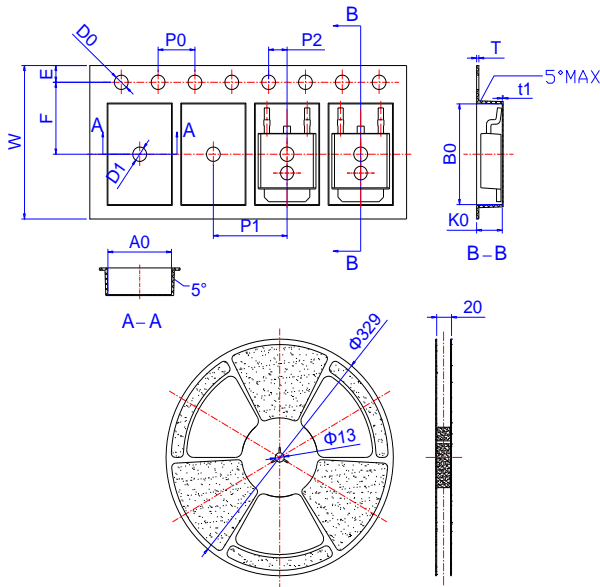
## 200V N-Channel Enhancement Mode MOSFET

### Package Mechanical Data



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.10		2.50	0.083		0.098
A2	0		0.10	0		0.004
B	0.66		0.86	0.026		0.034
B2	5.18		5.48	0.202		0.216
C	0.40		0.60	0.016		0.024
C2	0.44		0.58	0.017		0.023
D	5.90		6.30	0.232		0.248
D1	5.30REF			0.209REF		
E	6.40		6.80	0.252		0.268
E1	4.63			0.182		
G	4.47		4.67	0.176		0.184
H	9.50		10.70	0.374		0.421
L	1.09		1.21	0.043		0.048
L2	1.35		1.65	0.053		0.065
V1		7°			7°	
V2	0°		6°	0°		6°

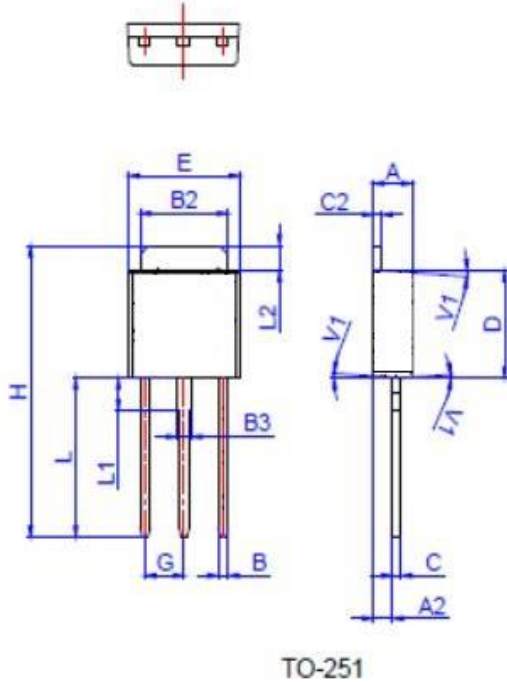
### Reel Specification-TO-252



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
B0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
T	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583

## 200V N-Channel Enhancement Mode MOSFET

### Package Mechanical Data



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	2.20		2.40	0.086		0.095
A2	0.90		1.20	0.035		0.047
B	0.55		0.65	0.022		0.026
B2	5.10		5.40	0.200		0.213
B3	0.76		0.85	0.030		0.033
C	0.45		0.62	0.018		0.024
C2	0.48		0.62	0.019		0.024
D	6.00		6.20	0.236		0.244
E	6.40		6.70	0.252		0.264
G		2.30			0.091	
H	16.0		17.0	0.630		0.669
L	8.90		9.40	0.350		0.370
L1	1.80		1.90	0.071		0.075
L2	1.37		1.50	0.054		0.059
V1		4°			4°	

### Package Information -TO-251

OUTLINE	TUBE (PCS)	INNER BOX (PCS)	PER CARTON (PCS)
TUBE	80	4,000	32,000

**200V N-Channel Enhancement Mode MOSFET****Attention**

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